

VLSI testing - Lab 1 & 2

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- pre_norm: Noscan vs. Scanned (DC+TMAX)

	Area	Power (W)	Fault count	Coverage (collapsed) (%)	ATPG Run Time(s)	Pattern
NonScanned	98072	260u	4011	98.05	7137.43	279
Scanned	105072	271u	4415	99.34	0.72	159

- s38584_seq: Noscan vs. Scanned (DC+TMAX)

	Area	Power (W)	Fault count	Coverage (collapsed) (%)	ATPG Run Time(s)	Pattern
NonScanned	1081468	1.8636m	55680	10.75	89754.29	6
Scanned	1223322	5.8111m	42188	100	1.32	136

- different design flows for pre_norm

Flow	#Faults	Test Coverage (%)	#Patterns	Run time (s)
DC+TMAX	4415	99.34	159	0.72
DFT+FS	6098	99.73	192	5.5
DC+FS	6012	99.85	195	4.4